











SN74CBT3251

SCDS019M - MAY 1995-REVISED DECEMBER 2015

SN74CBT3251 1-of-8 FET Multiplexer and Demultiplexer

Features

- 5-Ω Switch Connection Between Two Ports
- TTL-Compatible Input Levels
- Low Crosstalk Between Switches
- Fast Switching and Propagation Speeds
- **Operating Temperature Range:** -40°C to 85°C

2 Applications

- Digital Radio
- Signal Gating
- **Factory Automation**
- **Televisions**
- **Appliances**
- Programmable Logic Circuits
- Sensors

3 Description

The SN74CBT3251 is a 1-of-8 high-speed TTLcompatible FET multiplexer and demultiplexer. The low ON-state resistance of the switch allows connections to be made with minimal propagation delay.

When output enable (OE) is low, the SN74CBT3251 is enabled, and S0, S1, and S2 select one of the B outputs for the A-input data.

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
SN74CBT3251RGY	VQFN (16)	3.50 mm × 4.00 mm
SN74CBT3251DBQ	SSOP (16)	3.90 mm × 4.90 mm
SN74CBT3251PW	TSSOP (16)	4.40 mm × 5.00 mm
SN74CBT3251DB	SSOP (16)	5.30 mm × 6.20 mm
SN74CBT3251D	SOIC (16)	3.91 mm × 9.90 mm

⁽¹⁾ For all available packages, see the orderable addendum at the end of the data sheet.

Functional Diagram of the SN74CBT3251

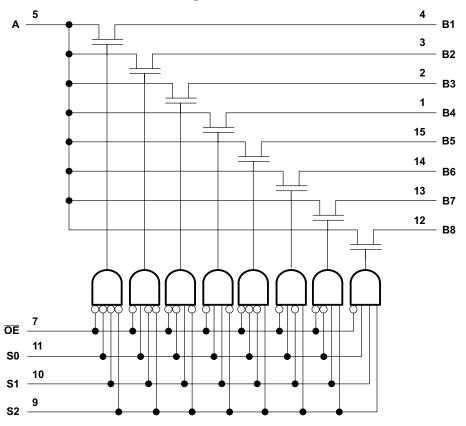




Table of Contents

1	Features 1		8.3 Feature Description	7
2			8.4 Device Functional Modes	
3	Applications 1 Description 1	9	Application and Implementation	
4	Revision History2		9.1 Application Information	8
5	Pin Configuration and Functions		9.2 Typical Application	8
6	Specifications	10	Power Supply Recommendations	9
U	6.1 Absolute Maximum Ratings	11	Layout	9
	6.2 ESD Ratings		11.1 Layout Guidelines	
	6.3 Recommended Operating Conditions		11.2 Layout Example	9
	6.4 Thermal Information	12	Device and Documentation Support	10
	6.5 Electrical Characteristics		12.1 Documentation Support	
	6.6 Switching Characteristics		12.2 Community Resources	
	6.7 Typical Characteristic		12.3 Trademarks	10
7	Parameter Measurement Information		12.4 Electrostatic Discharge Caution	10
8	Detailed Description 7		12.5 Glossary	10
Ü	8.1 Overview 7	13	Mechanical, Packaging, and Orderable Information	10
	8.2 Functional Block Diagram 7			

4 Revision History

Changes from Revision L (January 2004) to Revision M

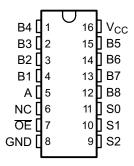
Page

Added ESD Ratings table, Feature Description section, Device Functional Modes, Application and Implementation section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and

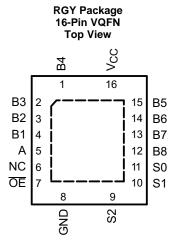


5 Pin Configuration and Functions

D, DB, DBQ, or PW Packages 16-Pin SOIC, SSOP, or TSSOP Top View



NC - No internal connection



NC - No internal connection

Pin Functions

PIN		1/0	DESCRIPTION				
NO.	NAME	I/O	DESCRIPTION				
1	B4	I/O	Port B4				
2	В3	I/O	Port B3				
3	B2	I/O	Port B2				
4	B1	I/O	Port B1				
5	Α	I/O	Common OUT/IN				
6	NC	_	No Connect				
7	ŌĒ	1	Enable Ports (Active Low). See Table 1.				
8	GND	_	Ground				
9	S2	I	Select Pin 2. See Table 1.				
10	S1	1	Select Pin 1. See Table 1.				
11	S0	1	Select Pin 0. See Table 1.				
12	B8	I/O	Port B8				
13	B7	I/O	Port B7				
14	B6	I/O	Port B6				
15	B5	I/O	Port B5				
16	V _{CC}	_	Power Pin				



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

	MIN	MAX	UNIT
Supply voltage, V _{CC}	-0.5	7	V
Input voltage, V ₁ ⁽²⁾	-0.5	7	V
Continuous channel current		128	mA
Input clamp current, I _K (V _{I/O} < 0)		-50	mA
Maximum junction temperature, T _J		150	°C
Storage temperature, T _{stg}	-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

				VALUE	UNIT
١,	. /	Electrostatic	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1)	±1500	V
	V _(ESD)	discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 (2)	±1000	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	4	5.5	V
V_{IH}	High-level control input voltage	2		V
V_{IL}	Low-level control input voltage		8.0	V
T _A	Operating free-air temperature	-40	85	°C

6.4 Thermal Information

			SN7	74CBT3251			
	THERMAL METRIC ⁽¹⁾	D (SOIC)	DB (SSOP)	DBQ (SSOP)	PW (TSSOP)	RGY (VQFN)	UNIT
		16 PINS	16 PINS	16 PINS	16 PINS	16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	73 ⁽²⁾	82 ⁽²⁾	90(2)	108 ⁽²⁾	39 ⁽³⁾	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	70.6	49.0	59.0	41.6	52.8	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	77.8	49.4	50.1	51.9	20.4	°C/W
ΨЈТ	Junction-to-top characterization parameter	24.3	10.5	13.9	4.0	1.1	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	77.4	48.8	49.7	51.3	20.4	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	_	_	_	_	6.4	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report, SPRA953.

²⁾ The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

The package thermal impedance is calculated in accordance with JESD 51-7.

⁽³⁾ The package thermal impedance is calculated in accordance with JESD 51-5.



6.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CONDITIONS		MIN	TYP ⁽¹⁾	MAX	UNIT
V _{IK}		V _{CC} = 4.5 V, I _I = −18 mA					-1.2	V
I		$V_{CC} = 5.5 \text{ V}, V_{I} = 5.5 \text{ V}$	or GND				±1	μΑ
I _{CC}		$V_{CC} = 5.5 \text{ V}, I_{O} = 0, V_{I} =$	VCC or GND				3	μΑ
$\Delta I_{CC}^{(2)}$	Control inputs	V _{CC} = 5.5 V; One input a	V_{CC} = 5.5 V; One input at 3.4 V, other inputs at V_{CC} or GND				2.5	mA
C _i	Control inputs	V _I = 3 V or 0	V _i = 3 V or 0					pF
_	A port	$V_O = 3 \text{ V or } 0, \overline{OE} = V_{CC}$				17.5		pF
C _{io(OFF)}	B port	$V_O = 3 \text{ V or } 0, \overline{OE} = V_{CC}$	$V_O = 3 \text{ V or } 0, \overline{OE} = V_{CC}$			4		þг
		V_{CC} = 4 V, TYP at V_{CC} =	$4 \text{ V}, \text{ V}_{\text{I}} = 2.4 \text{ V}, \text{ I}_{\text{I}} = 15$	mA		14	20	
r _{on} (3)			V _I = 0	I _I = 64 mA		5	7	Ω
lon`′		$V_{CC} = 4.5 \text{ V}$	v ₁ = 0	I _I = 30 mA		5	7	77
			$V_I = 2.4 \text{ V}, I_I = 15 \text{ m}$	Α		10	15	

- All typical values are at $V_{CC} = 5$ V (unless otherwise noted), $T_A = 25$ °C. This is the increase in supply current for each input at the specified TTL voltage level, rather than V_{CC} or GND. Measured by the voltage drop between the A and the B terminals at the indicated current through the switch. On-state resistance is determined by the lower of the voltages of the two (A or B) terminals.

6.6 Switching Characteristics

over operating free-air temperature free-air temperature range, $C_L = 50$ pF (unless otherwise noted)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{cc}	MIN	MAX	UNIT
t _{pd} ⁽¹⁾	A or B	B or A	V _{CC} = 4 V		0.35	20
^l pd` ′	AUID	B OF A	$V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$		0.24	ns
4	S	A	$V_{CC} = 4 V$		6	20
t _{pd}	3	A	$V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$	2	5.5	ns
	S	В	$V_{CC} = 4 V$		6.4	
	en <u>OE</u>	Б	$V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$	1.5	5.6	ns
^l en		A or B	$V_{CC} = 4 V$		6.4	
		AUID	$V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$	1.6	5.8	
	S	В	$V_{CC} = 4 V$		6.8	
t _{dis}	3	Б	$V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$	1.9	6.4	ns
	ŌĒ	A or B	$V_{CC} = 4 V$		6	
	OE .	AUID	$V_{CC} = 5 \text{ V } \pm 0.5 \text{ V}$	2.3	6.2	

⁽¹⁾ The propagation delay is the calculated RC time constant of the typical on-state resistance of the switch and the specified load capacitance, when driven by an ideal voltage source (zero output impedance).

6.7 Typical Characteristic

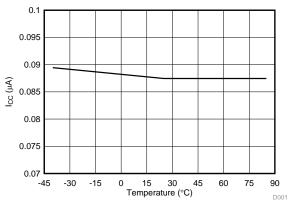
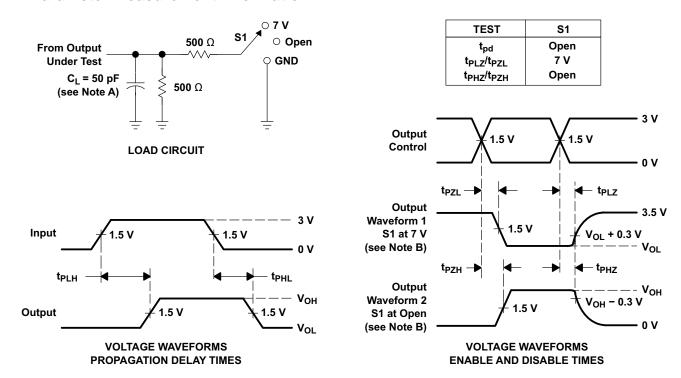


Figure 1. I_{CC} Variation With Temperature

TEXAS INSTRUMENTS

7 Parameter Measurement Information



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , $t_r \leq$ 2.5 ns. $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis}.
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .
- H. All parameters and waveforms are not applicable to all devices.

Figure 2. Load Circuit and Voltage Waveforms

Submit Documentation Feedback



8 Detailed Description

8.1 Overview

The SN74CBT3251 device is a single 8-channel multiplexer with three binary control inputs, S_0 , S_1 , and S_2 and an \overline{OE} (output enable, active low) input. The three binary signals select 1 of 8 channels to be turned on, and connect one of the 8 inputs to the output.

When they are used as demultiplexers, the CHANNEL IN/OUT terminals (B) are the outputs and the COMMON OUT/IN terminal (A) is the input.

8.2 Functional Block Diagram

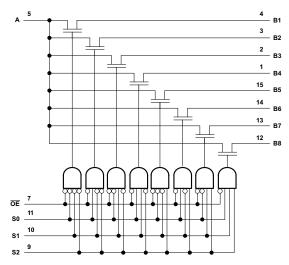


Figure 3. Logic Diagram (Positive Logic)

8.3 Feature Description

The SN74CBT3251 1-of-8 FET multiplexers and demultiplexers can accept a wide range of analog signal levels from 0 V to 5 V. It has low Ron resistance, typically 5- Ω for V_{CC} = 5 V which allows very little signal loss through the switch. Binary address decoding on chip makes channel selection easy.

8.4 Device Functional Modes

Table 1 lists the functional modes of the SN74CBT3251.

Table 1. Function Table (Each Multiplexer and Demultiplexer)

	INPUTS							
ŌĒ	S2	S1	S0	FUNCTION				
L	L	L	L	A port = B1 port				
L	L	L	Н	A port = B2 port				
L	L	Н	L	A port = B3 port				
L	L	Н	Н	A port = B4 port				
L	Н	L	L	A port = B5 port				
L	Н	L	Н	A port = B6 port				
L	Н	Н	L	A port = B7 port				
L	Н	Н	Н	A port = B8 port				
Н	X	X	X	Disconnect				



9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The SN74CBT351 device can be used for a wide variety of applications, including expanding MCU GPIOs.

9.2 Typical Application

One application of the SN74CBT3251 device is to use in conjunction with a microcontroller to poll a keypad. Figure 4 shows the basic schematic for such a polling system. The microcontroller uses the channel-select pins to cycle through the different channels while reading the input to see if a user is pressing any of the keys. This is a very robust setup that allows for simultaneous key presses with very little power consumption. It also uses very few pins on the microcontroller. The down side of polling is that the microcontroller must frequently scan the keys for a press.

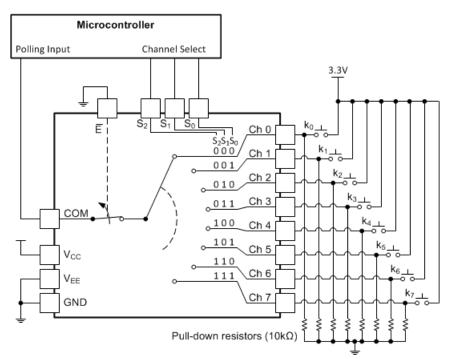


Figure 4. Keypad Polling Application

9.2.1 Design Requirements

These devices use CMOS technology and have balanced output drive. Take care to avoid bus contention because it can drive currents that would exceed maximum limits.

9.2.2 Detailed Design Procedure

- 1. Recommended input conditions:
 - For switch time specifications, see propagation delay times in Recommended Operating Conditions.
 - Inputs must not be pulled below ground.
 - For input voltage level specifications for control inputs, see V_{IH} and V_{IL} in Recommended Operating Conditions.



Typical Application (continued)

- 2. Input and output current consideration:
 - Load currents must not exceed per output and must not exceed (Continuous current through V_{CC} or GND) total current for the part. These limits are located in Absolute Maximum Ratings.

9.2.3 Application Curve

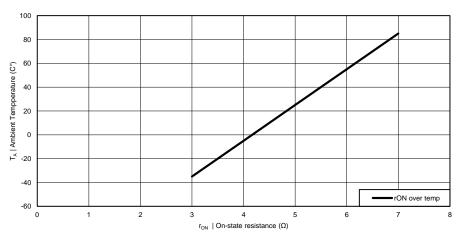


Figure 5. r_{ON} Over Temperature

10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in *Recommended Operating Conditions*.

Each V_{CC} pin should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, a 0.1- μ F capacitor is recommended and if there are multiple V_{CC} pins then a 0.01- μ F or 0.022- μ F capacitor is recommended for each power pin. It is ok to parallel multiple bypass caps to reject different frequencies of noise. 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power pin as possible for best results.

11 Layout

11.1 Layout Guidelines

When using multiple bit logic devices inputs must not ever float. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. Specified below are the rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that should be applied to any particular unused input depends on the function of the device. Generally they will be tied to GND or V_{CC} whichever make more sense or is more convenient.

11.2 Layout Example



Figure 6. Layout Diagram



12 Device and Documentation Support

12.1 Documentation Support

12.1.1 Related Documentation

For related documentation, see the following:

Implications of Slow or Floating CMOS Inputs, SCBA004

12.2 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.3 Trademarks

E2E is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

12.4 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

12.5 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser based versions of this data sheet, refer to the left hand navigation.

13-Aug-2021

www.ti.com

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing		Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
	(-)		J		-	(-)	(6)	(5)		()	
SN74CBT3251D	ACTIVE	SOIC	D	16	40	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CBT3251	Samples
SN74CBT3251DBQR	ACTIVE	SSOP	DBQ	16	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	CU251	Samples
SN74CBT3251DBQRG4	ACTIVE	SSOP	DBQ	16	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	CU251	Samples
SN74CBT3251DBR	ACTIVE	SSOP	DB	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CU251	Samples
SN74CBT3251DE4	ACTIVE	SOIC	D	16	40	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CBT3251	Samples
SN74CBT3251DR	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CBT3251	Samples
SN74CBT3251PW	ACTIVE	TSSOP	PW	16	90	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CU251	Samples
SN74CBT3251PWR	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CU251	Samples
SN74CBT3251RGYR	ACTIVE	VQFN	RGY	16	3000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	CU251	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.



PACKAGE OPTION ADDENDUM

www.ti.com 13-Aug-2021

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 3-Jun-2022

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74CBT3251DBQR	SSOP	DBQ	16	2500	330.0	12.5	6.4	5.2	2.1	8.0	12.0	Q1
SN74CBT3251DBR	SSOP	DB	16	2000	330.0	16.4	8.35	6.6	2.4	12.0	16.0	Q1
SN74CBT3251DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
SN74CBT3251PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74CBT3251RGYR	VQFN	RGY	16	3000	330.0	12.4	3.8	4.3	1.5	8.0	12.0	Q1



www.ti.com 3-Jun-2022



*All dimensions are nominal

7 III GITTOTOTOTO GITO TIOTITICA							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74CBT3251DBQR	SSOP	DBQ	16	2500	340.5	338.1	20.6
SN74CBT3251DBR	SSOP	DB	16	2000	356.0	356.0	35.0
SN74CBT3251DR	SOIC	D	16	2500	340.5	336.1	32.0
SN74CBT3251PWR	TSSOP	PW	16	2000	356.0	356.0	35.0
SN74CBT3251RGYR	VQFN	RGY	16	3000	367.0	367.0	35.0

PACKAGE MATERIALS INFORMATION

www.ti.com 3-Jun-2022

TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
SN74CBT3251D	D	SOIC	16	40	507	8	3940	4.32
SN74CBT3251DE4	D	SOIC	16	40	507	8	3940	4.32
SN74CBT3251PW	PW	TSSOP	16	90	530	10.2	3600	3.5

D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.







- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.







- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
 4. Reference JEDEC registration MO-150.





NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.





SHRINK SMALL-OUTLINE PACKAGE



- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 inch, per side.
- 4. This dimension does not include interlead flash.5. Reference JEDEC registration MO-137, variation AB.



SHRINK SMALL-OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SHRINK SMALL-OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) package configuration.
- D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- Pin 1 identifiers are located on both top and bottom of the package and within the zone indicated. The Pin 1 identifiers are either a molded, marked, or metal feature.
- G. Package complies to JEDEC MO-241 variation BA.



RGY (R-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No—Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

Exposed Thermal Pad Dimensions

4206353-3/P 03/14

NOTE: All linear dimensions are in millimeters



RGY (R-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat—Pack QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com http://www.ti.com.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2022, Texas Instruments Incorporated